## Notice of References Cited Application/Control No. 10/580,832 Examiner JENNIFER DOAN Applicant(s)/Patent Under Reexamination SUH ET AL. Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-7,357,510 B2	04-2008	Kim et al.	353/7
*	В	US-6,513,953 B1	02-2003	Itoh, Yoshitaka	362/331
	O	US-			
	ם	US-			
	Е	US-			
	F	US-			
	G	US-			
	Ι	US-		1	
	_	US-			
	7	US-			
	K	US-	1		
	Ш	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
6	R					
	s					
	I				100	

## NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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